

# Device Modeling Report

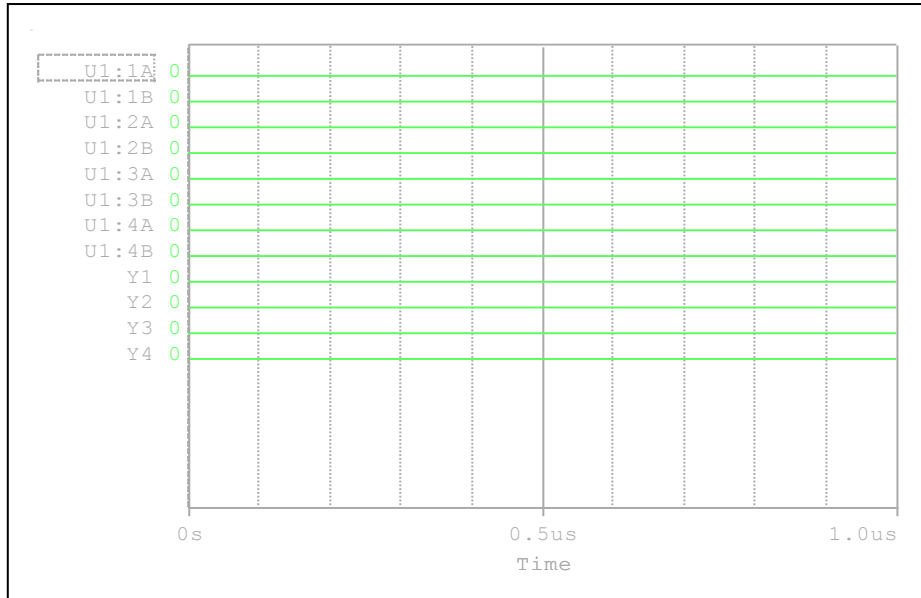
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT  
PART NUMBER : TC74HC08AP  
MANUFACTURER : TOSHIBA



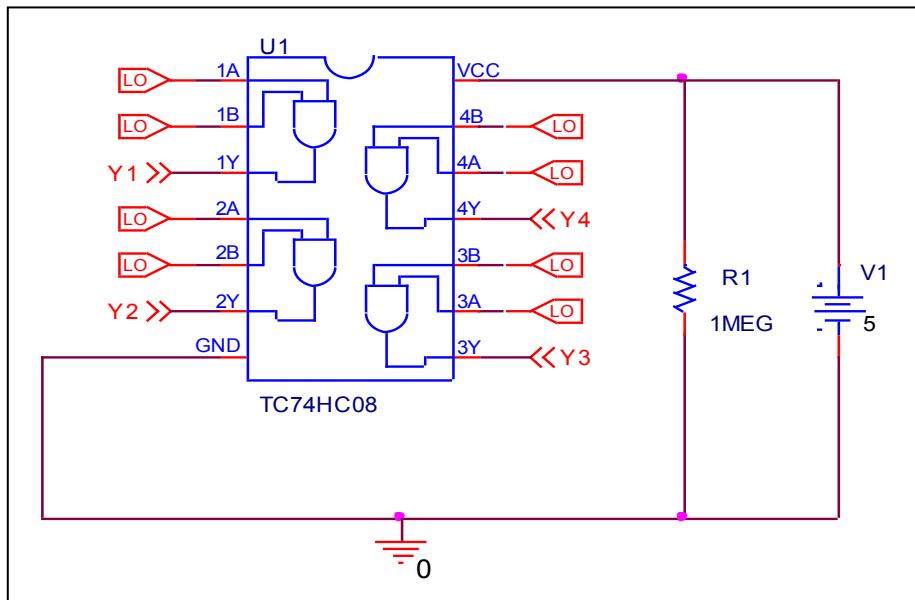
**Bee Technologies Inc.**

# Truth Table

## Circuit simulation result



## Evaluation circuit

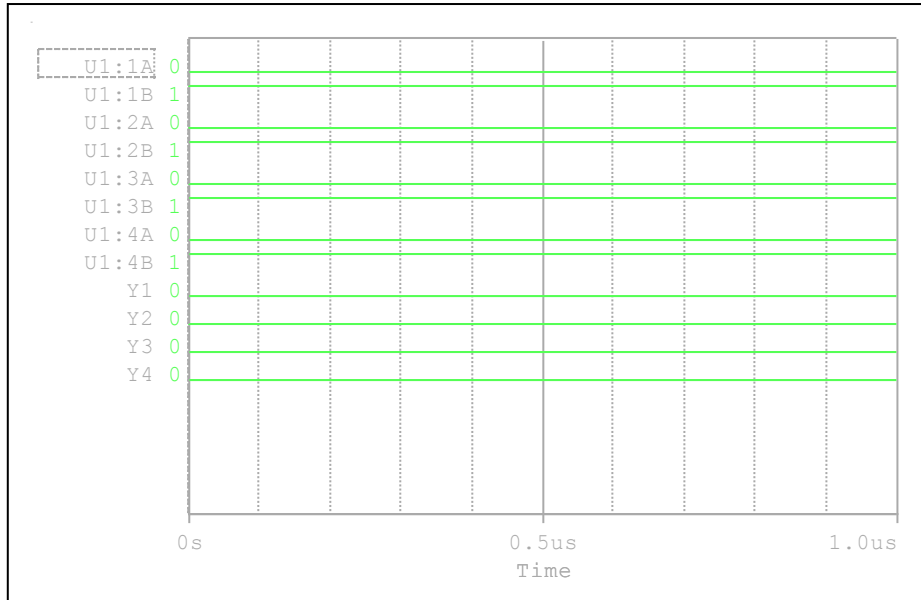


## Comparison table

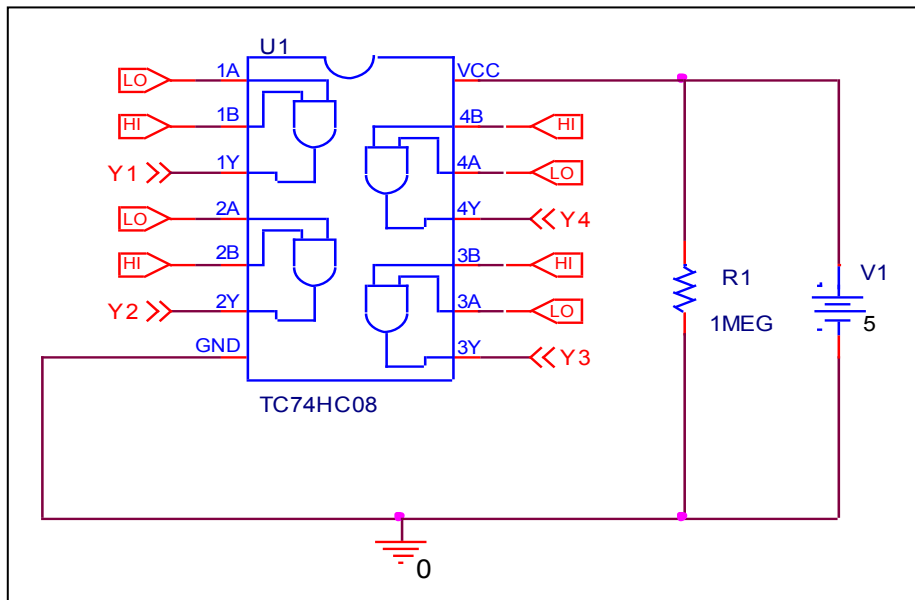
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
L	L	L	L	0

# Truth Table

## Circuit simulation result



## Evaluation circuit

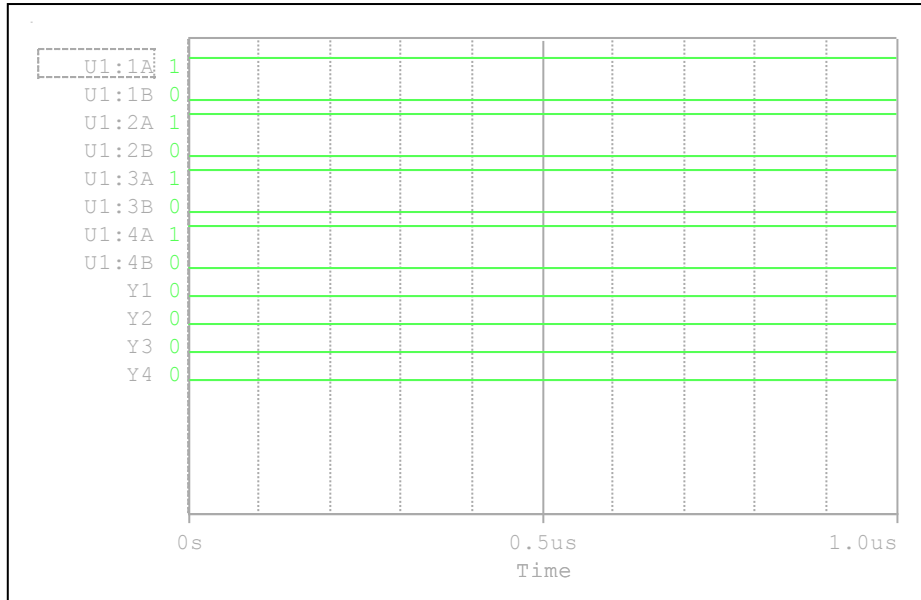


## Comparison table

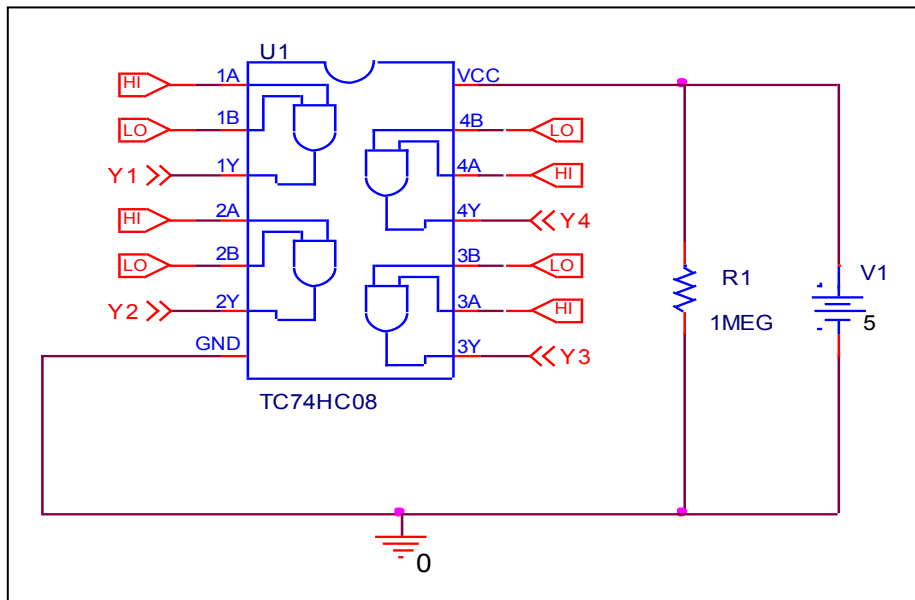
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
L	H	L	L	0

# Truth Table

## Circuit simulation result



## Evaluation circuit

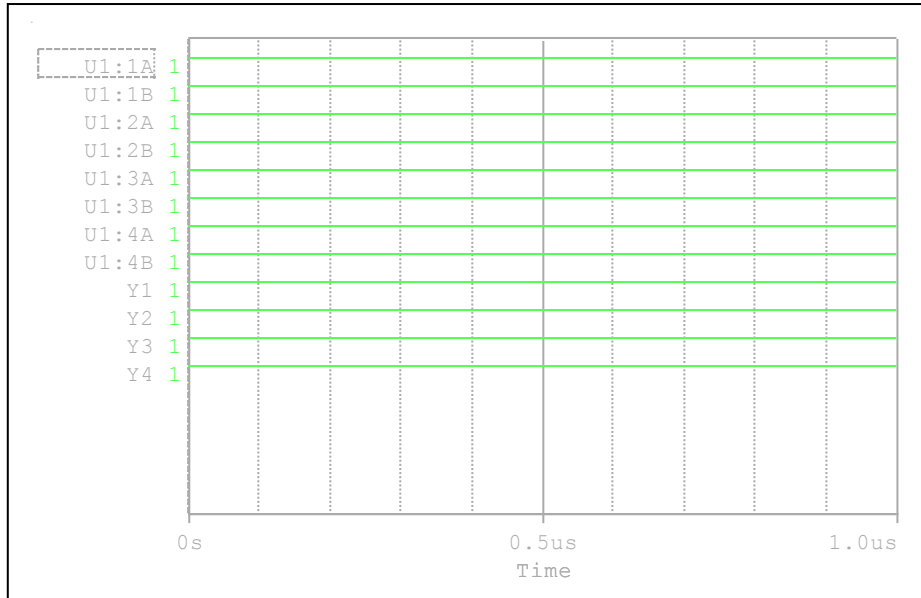


## Comparison table

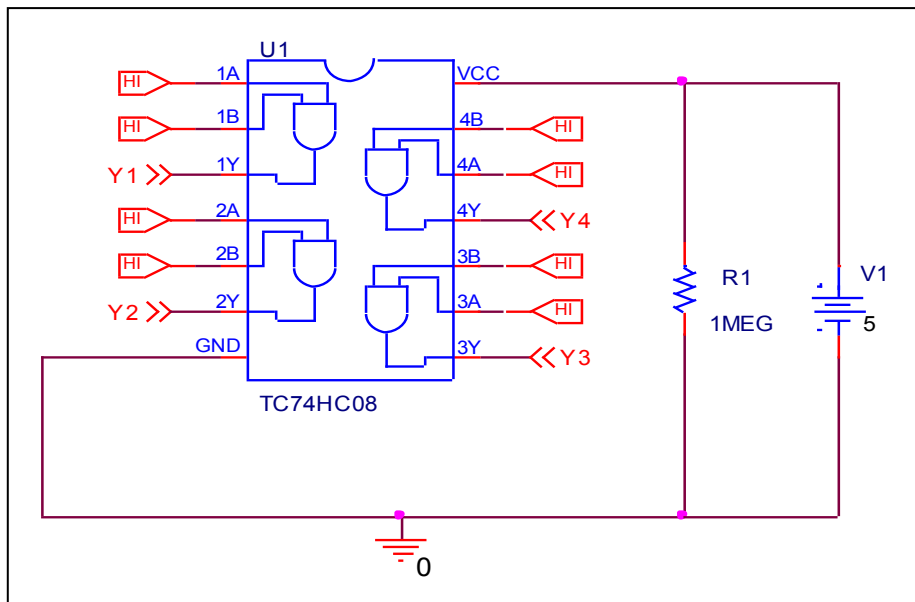
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
H	L	L	L	0

# Truth Table

## Circuit simulation result



## Evaluation circuit

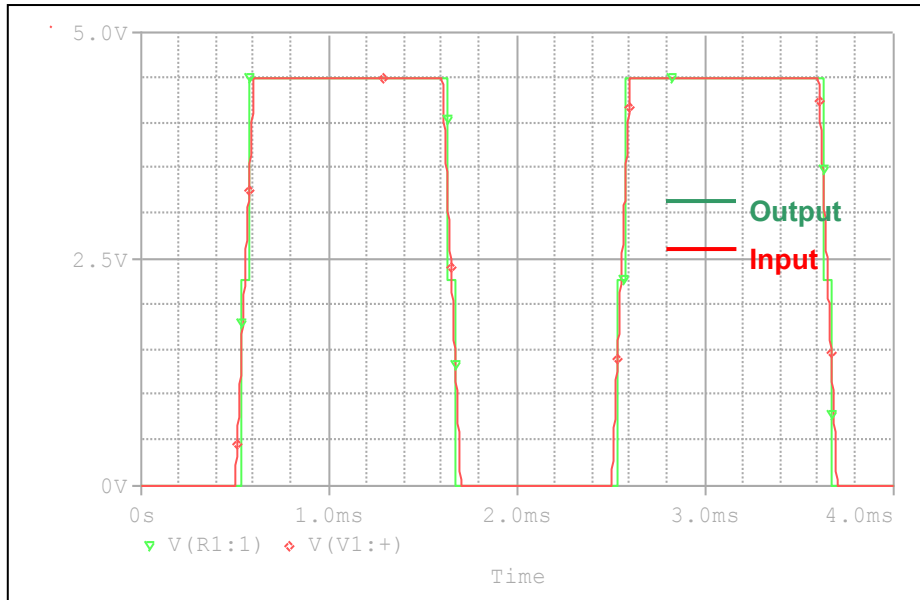


## Comparison table

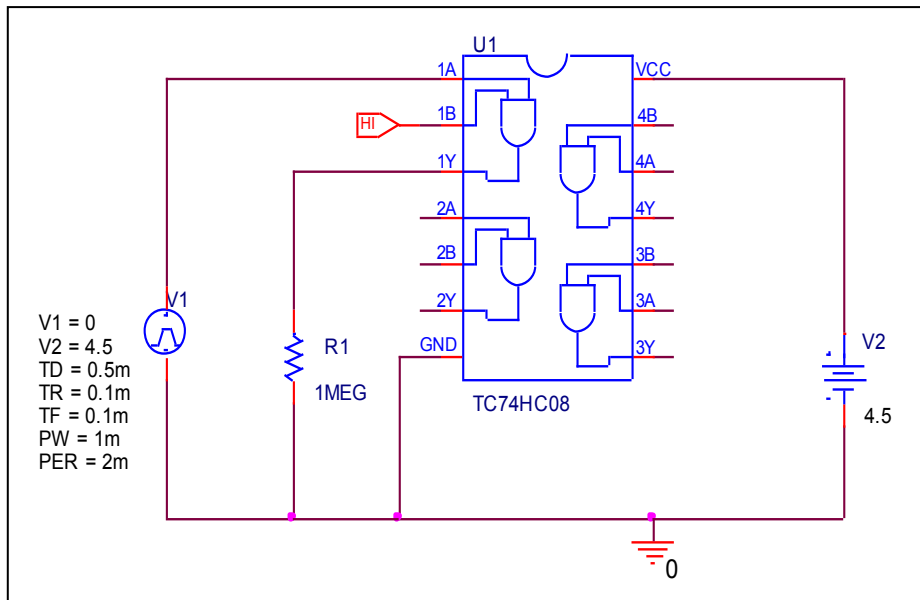
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
H	H	H	H	0

# High Level and Low Level Input Voltage

## Circuit simulation result



## Evaluation circuit

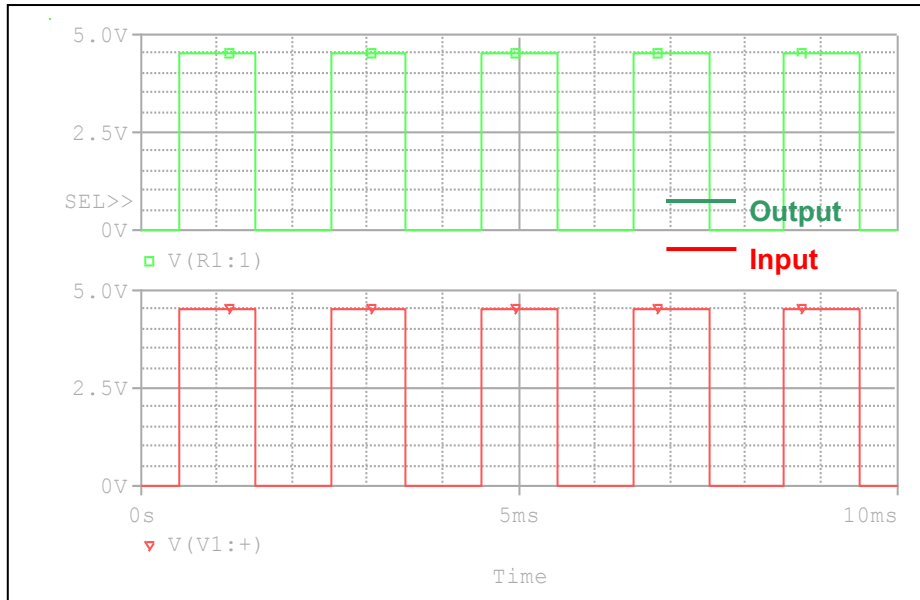


## Comparison table

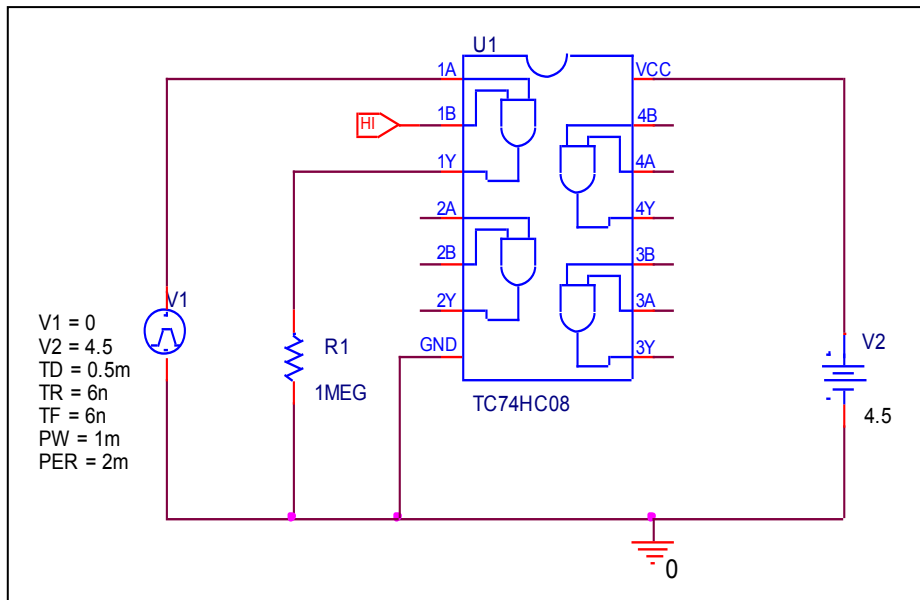
$V_{CC} = 4.5V$	Measurement	Simulation	%Error
$V_{IH} (V)$	3.15	3.1505	0.016
$V_{IL} (V)$	1.35	1.3454	-0.341

# High Level and Low Level Output Voltage

## Circuit simulation result



## Evaluation circuit

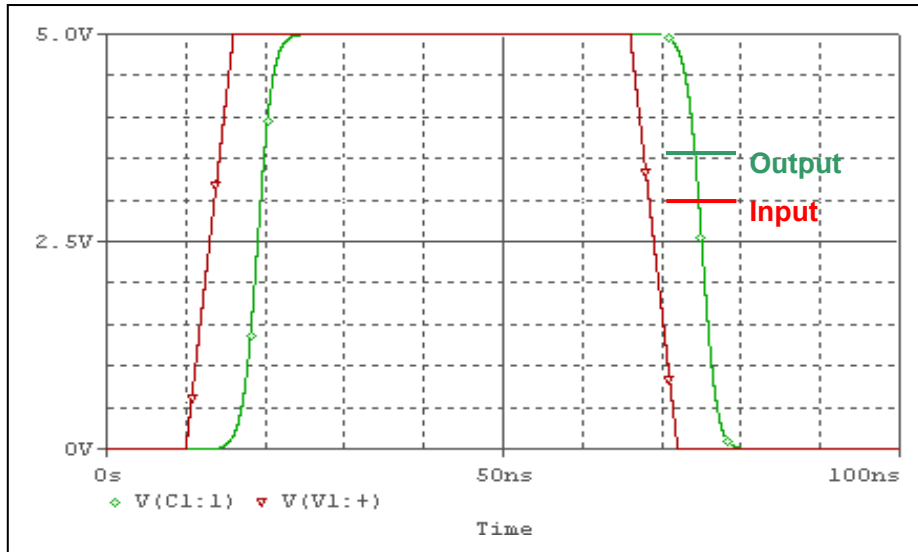


## Comparison table

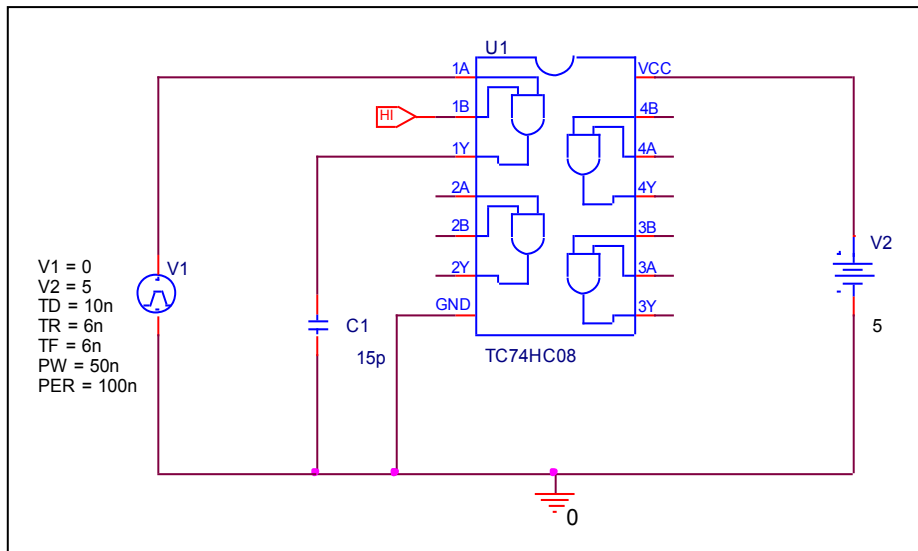
$V_{CC} = 4.5V$	Measurement	Simulation	%Error
$V_{OH} (V)$	4.5	4.4975	-0.056
$V_{OL} (V)$	0	0	0

# Propagation Delay Time

## Circuit simulation result



## Evaluation circuit



## Comparison table

$C_L=15pF, V_{CC} = 5V, tr=tf=6ns$	Measurement	Simulation	%Error
$t_{TLH}$ (ns)	4	4.0014	0.035
$t_{THL}$ (ns)	4	4.0169	0.422
$T_{pLH}$ (ns)	6	6.0612	1.020
$T_{pHL}$ (ns)	6	6.0398	0.663